

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	9253968	semiconductor or integrated adj circuit \$1 or ic\$1 or die\$1 or dice\$1 or wafer or component\$1 or dut \$1 or device\$1 adj under adj test\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/07/02 12:51
L2	4531219	1 and (prob\$4 or contact\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/07/02 12:52
L3	721023	2 and (pcb or board \$1 or card\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/07/02 12:54
L4	17847	3 and anisotropic\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/07/02 13:00
L5	14803	4 and (electrode\$1 or pad\$1 or terminal \$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/07/02 13:01
L6	556	5 and ((parallel\$3 or horizont\$4) near (adjust\$4 or align \$4))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/07/02 13:02
L7	148	6 and conduct\$4 near film\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/07/02 13:03
L8	137	7 and (hole\$1 or aperture\$1 or open \$1 or opening\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/07/02 13:03

L9	39	8 and elast\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/07/02 13:04
L10	640723	(igarashi or sato or inoue).in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/07/02 13:07
L11	16442	10 and (hisao or katsumi or kazuo)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/07/02 13:08
L12	236	11 and probe	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/07/02 13:08
L13	58	12 and anisotropic\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/07/02 13:08

7/2/08 1:15:35 PM